PATENT NUMBER

ISSUE CLASSIFICATION

Subclass

Class

1-021 U.S PTO
09/976739
10/17/03

U.S. UTILITY Patent Application

	O.I.P.E.	PATENT DATE
	SCANNED TD3 Q.A.	

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/976739		382	149	2623	J. Marosso
					QIANGSHAN

APPLICANTS

Christopher Wooten
Arturo Morosoff

TITLE Method for evaluating anomalies in a semiconductor manufacturing process

PTO-2040
12/99

ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)		
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)	

INTERNATIONAL CLASSIFICATION

☐ Continued on Issue Slip Inside File Jacket

☐ **TERMINAL DISCLAIMER**

☐ The term of this patent subsequent to _____ (date) has been disclaimed.

☐ The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____

☐ The terminal ____ months of this patent have been disclaimed.

DRAWINGS		
Sheets Drwg.	Figs. Drwg.	Print Fig.
(Assistant Examiner)		(Date)
(Primary Examiner)		(Date)
(Legal Instruments Examiner)		(Date)

CLAIMS ALLOWED	
Total Claims	Print Claim for O.G.

NOTICE OF ALLOWANCE MAILED

ISSUE FEE

Amount Due	Date Paid

ISSUE BATCH NUMBER

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